

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		DOCKET NO. 5988-036-27		SERIAL NO. 09/987,916	
LIST OF REFERENCES CITED BY APPLICANT (Use Several Sheets if Necessary)				APPLICANT AKI SUZUKI, ET AL.		GROUP ART UNIT 1752	
				FILING DATE NOVEMBER 16, 2001			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ACW	AA	5,238,774	08/24/93	Hosaka, et al.			
	AB	5,215,857	06/01/93	Hosaka, et al.			
	AC	5,405,720	04/11/95	Hosaka, et al.			
	AD	5,494,784	02/27/96	Hosaka, et al.			
	AE	5,925,492	07/20/99	Hosaka, et al.			
	AF	6,020,104	02/01/00	Hosaka, et al.			
	AG	6,228,554 B1	05/08/01	Hosaka, et al.			
	AH	6,280,900 B1	08/28/01	Chiba, et al.			
	AI	6,270,939 B1	08/07/01	Hosaka, et al.			
	AJ	6,337,171 B1	01/08/02	Kobayashi, et al.			
ACW	AK	RE37,179 E	05/15/01	Yamachika, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
ACW	AL	60-191372	09/28/85	Japan	Abstract		
	AM	61-212131	09/20/86	Japan	Abstract		
	AN	03-232652	10/16/91	Japan	Abstract		
	AO	2000-284482	10/13/00	Japan	Abstract		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AP	Jiro NAKAMURA, et al., "Resist Surface Roughness Calculated using Theoretical Percolation Model", Journal of Photopolymer Science and Technology, Vol. 11, No. 4, pp. 571-576, (1998).					
	AQ	Peter ZANDBERGEN, et al., "Characterization and optimization of positive tone DUV resists on TiN substrates", SPIE Vol. 3049, pp. 314-323.					
	AR	Eishi SHIOBARA, et al., "Resist Edge Roughness with Reducing Pattern Size", SPIE Vol. 3333, pp. 313-323.					
V	AS	S.C. PALMATEER, et al., "Line Edge Roughness in sub-0.18- μ m Resist Patterns", SPIE Vol. 3333, pp. 634-642.					
ACW	AT	Hideo NAMATSU, et al., "Three-dimensional siloxane resist for the formation of nanopatterns with minimum linewidth fluctuations", J. Vac. Sci. Technol. B, Vol. 16, No. 1, pp. 69-76 (1998).					
EXAMINER <i>John C. Walk</i>					DATE CONSIDERED <i>March 26, 2003</i>		
<p>*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.</p>							



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LIST OF RELATED CASES

Docket Number	Serial or Patent Number	Filing or Issue Date	Status or Patentee
APW 311-140-0 FWC I	5,215,857	June 1, 1993	Patented
311-231-0 CONT	5,238,774	August 24, 1993	Patented
311-264-0 CONT	08/053,500	April 28, 1993	Pending
311-280-0 CONT	5,405,720	April 11, 1995	Patented
311-297-0 CONT	5,494,784	February 27, 1996	Patented
311-320-0 FWC	5,925,492	July 20, 1999	Patented
311-357-0	08/797,620	February 7, 1997	Pending
311-403-27 CONT	09/197,699	November 23, 1998	Pending
311-424-0 CONT	6,020,104	February 1, 2000	Patented
5988-016-27 CONT	6,228,554 B1	May 8, 2001	Patented
5988-018-27 REISSUE	RE37,179 E	May 15, 2001	Patented
5988-019-27	6,337,171 B1	January 8, 2002	Patented
5988-021-27	6,280,900 B1	August 28, 2001	Patented
5988-022-27	09/558,067	April 26, 2000	Pending
5988-023-27 CONT	6,270,939 B1	August 7, 2001	Patented
5988-024-27	09/662,160	September 14, 2000	Pending
5988-026-27	09/707,939	November 8, 2000	Pending
5988-028-27	09/741,334	December 21, 2000	Pending
5988-029-27	09/774,714	February 1, 2001	Pending
5988-030-27	09/824,224	April 3, 2001	Pending
DM 5988-031-37	09/874,977	June 7, 2001	Pending

5988-032-27	09/878,274	June 12, 2001	Pending
5988-033-27	09/879,894	June 14, 2001	Pending
5988-034-27	09/953,941	September 18, 2001	Pending
5988-036-27*	09/987,916	November 16, 2001	Pending

The cases listed on this Notice of Related Cases include cases which may contain information that is material to patentability. The listing of a case on this Notice should not be taken as an indication or admission that any information contained therein is material. Prior art for each case listed on this Notice may have been cited. **The files corresponding to the listed cases, which are available to the Examiner, may not have not been examined to ascertain the materiality of any prior art therein.** Accordingly, the Examiner is requested to review the file for each case listed on this Notice in order to assess the materiality of such prior art.

*Present application; listed for information.